

MITSUBISHI LSiS M5M5188BP, J-15, -20, -25

65536-BIT (16384-WORD BY 4-BIT) CMOS STATIC RAM

DESCRIPTION

This is family of 16384 word by 4-bit static RAMs, fabricated with the high-performance CMOS silicon-gate MOS process and designed for high-speed application. These devices operate on a single 5V supply, and are directly TTL compatible. They include a power-down feature as well.

FEATURES

- Fast access time M5M5188BP, J-15 15 ns (max)
M5M5188BP, J-20 20 ns (max)
M5M5188BP, J-25 25 ns (max)
- Low power dissipation Active 300 mW (typ)
Stand by 5 μ W (typ)
- Power down by \bar{S}
- Single 5V power supply
- Fully static operation
Requires neither external clock nor refreshing
- All inputs and output are directly TTL compatible
- Easy memory expansion by chip-select (\bar{S}) input

APPLICATION

High-speed memory systems

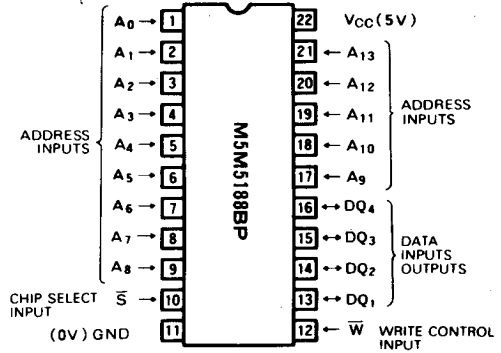
FUNCTION

A write operation is executed during the \bar{S} low and \bar{W} low overlap time. In this period, address signals must be stable. When \bar{W} is low, the DQ terminal is maintained in the high impedance state.

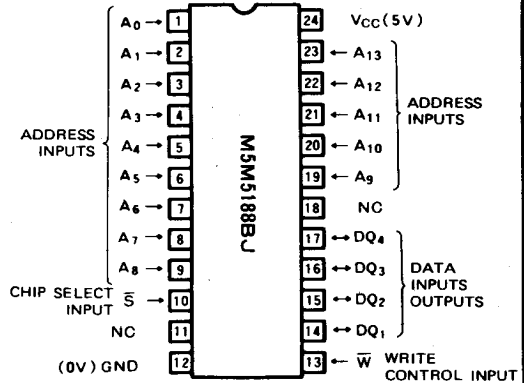
In a read operation, after setting \bar{W} to high, and \bar{S} to low if the address signals are stable, the data is available at the DQ terminal.

When \bar{S} is high, the chip is in the non-selectable state, disabling both reading and writing. In this case the output is in the floating (high-impedance) state, useful for OR-ties with other devices.

PIN CONFIGURATION (TOP VIEW)

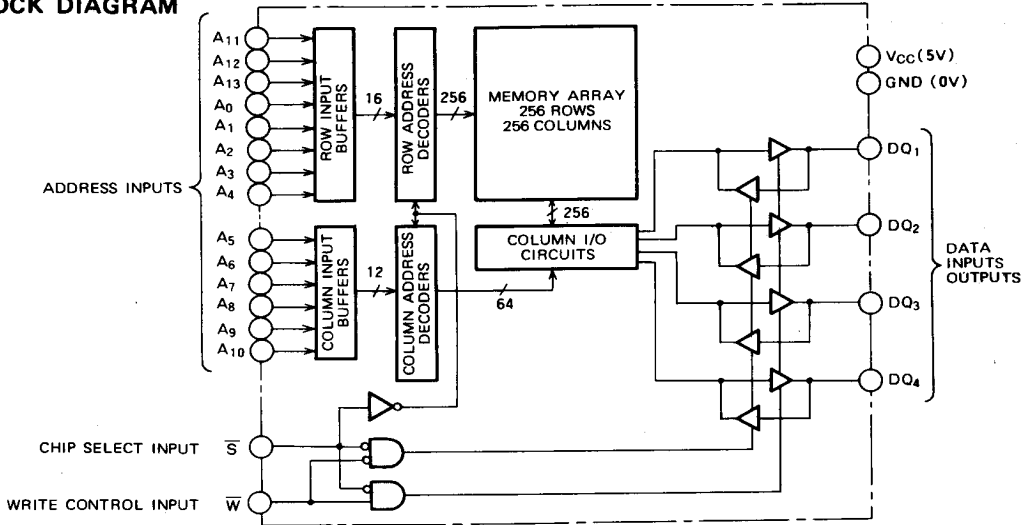


Outline 22P4H (DIP)



Outline 24P0J (SOJ) NC: NO CONNECTION

BLOCK DIAGRAM



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Signal \bar{S} controls the power-down feature. When \bar{S} goes high, power dissipation is reduced extremely. The access time from \bar{S} is equivalent to the address access time.

ABSOLUTE MAXIMUM RATINGS

Symbol	Parameter	Conditions	Ratings	Units
V_{CC}	Supply voltage	With respect to GND	$-3.5^* \sim 7$	V
V_I	Input voltage		$-3.5^* \sim 7$	V
V_O	Output voltage		$-3.5^* \sim 7$	V
P_d	Maximum power dissipation		1	W
T_{opr}	Operating temperature		$0 \sim 70$	$^{\circ}C$
$T_{stg}(\text{bias})$	Storage temperature (bias)		$-10 \sim 85$	$^{\circ}C$
T_{stg}	Storage temperature		$-65 \sim 150$	$^{\circ}C$

* Pulse width = 20ns. In case of DC: $-0.5V$

DC ELECTRICAL CHARACTERISTICS ($T_a = 0 \sim 70^{\circ}C$, $V_{CC} = 5V \pm 10\%$, unless otherwise noted)

Symbol	Parameter	Test conditions	Limits			Unit
			Min	Typ	Max	
V_{IH}	High-level input voltage		2.2		$V_{CC} + 0.3$	V
V_{IL}	Low-level input voltage		-3^*		0.8	V
V_{OH}	High-level output voltage	$I_{OH} = -4mA$	2.4			V
V_{OL}	Low-level output voltage	$I_{OL} = 8mA$			0.4	V
I_I	Input current	$V_I = 0 \sim V_{CC}$			10	μA
$ I_{OZ} $	Off-state output current	$V_I(\bar{S}) = V_{IH}$, $V_O = 0 \sim V_{CC}$			10	μA
I_{CC1}	Supply current from V_{CC}	$V_I(\bar{S}) = V_{IL}$	AC (minimum cycle)		120	mA
		Output open	DC		50	60
I_{CC2}	Stand by current	$V_I(\bar{S}) = V_{IH}$	AC (minimum cycle)		40	mA
			Other $V_I \geq V_{IH}$ or $\leq V_{IL}$		30	mA
I_{CC3}	Stand by current	$V_I(\bar{S}) \geq V_{CC} - 0.2V$ Other $V_I \leq 0.2V$ or $V_I \geq V_{CC} - 0.2V$			10	mA
C_I	Input capacitance	$V_I = GND$, $V_I = 25mV_{rms}$, $f = 1MHz$			5	pF
C_O	Output capacitance	$V_O = GND$, $V_O = 25mV_{rms}$, $f = 1MHz$			7	pF

Note 1. Current flow into an IC is positive, out is negative.

* Pulse width = 20ns. In case of DC: $-0.5V$

SWITCHING CHARACTERISTICS ($T_a = 0 \sim 70^{\circ}C$, $V_{CC} = 5V \pm 10\%$, unless otherwise noted)

MEASUREMENT CONDITIONS

Input pulse levels $V_{IH} = 3V$, $V_{IL} = 0V$

Input rise and fall time 3ns

Input timing reference level 1.5V

Output timing reference level $V_{OH} = V_{OL} = 1.5V$

Output loads Fig. 1, Fig. 2

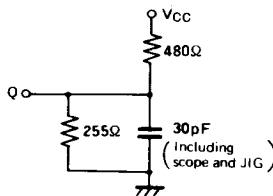


Fig. 1 Output load

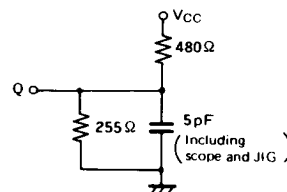


Fig. 2 Output load for t_{en} , t_{dis}

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READ CYCLE

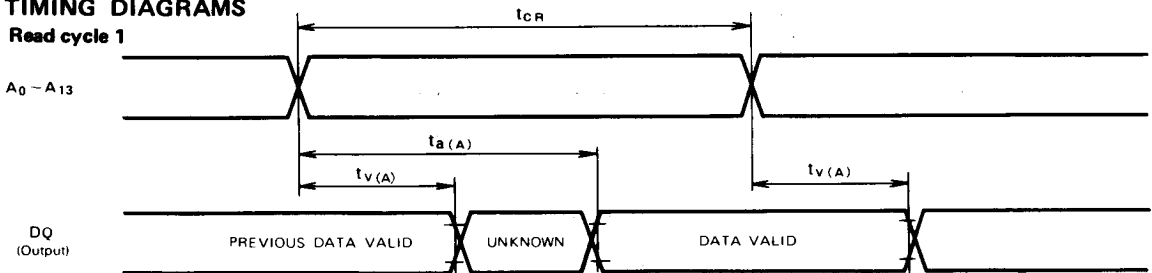
Symbol	Parameter	M5M5188B-15			M5M5188B-20			M5M5188B-25			Unit
		Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	
t_{CR}	Read cycle time	15			20			25			ns
$t_{a(A)}$	Address access time			15			20			25	ns
$t_{a(S)}$	Chip select access time			15			20			25	ns
$t_{v(A)}$	Data valid time after address	3			3			5			ns
$t_{en(S)}$	Output enable time after chip selection	3			3			5			ns
$t_{dis(S)}$	Output disable time after chip deselection	0		10	0		10	0		15	ns
t_{PU}	Power-up time after chip selection	0			0			0			ns
t_{PD}	Power down time after chip deselection			15			20			25	ns

WRITE CYCLE

Symbol	Parameter	M5M5188B-15			M5M5188B-20			M5M5188B-25			Unit
		Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	
t_{CW}	Write cycle time	15			20			25			ns
$t_{SU(S)}$	Chip select setup time	12			15			20			ns
$t_{SU(A)1}$	Address setup time 1 (\bar{W} CONTROL)	0			0			0			ns
$t_{SU(A)2}$	Address setup time 2 (\bar{S} CONTROL)	0			0			0			ns
$t_{W(W)}$	Write pulse width	12			15			20			ns
$t_{rec(W)}$	Write recovery time	0			0			0			ns
$t_{SU(D)}$	Data setup time	8			9			10			ns
$t_{h(D)}$	Data hold time	0			0			0			ns
$t_{dis(W)}$	Output disable time after \bar{W} low	0		8	0		8	0		10	ns
$t_{en(W)}$	Output enable time after \bar{W} high	0			0			0			ns
$t_{SU(A-\bar{W}H)}$	Address to \bar{W} high	12			15			20			ns

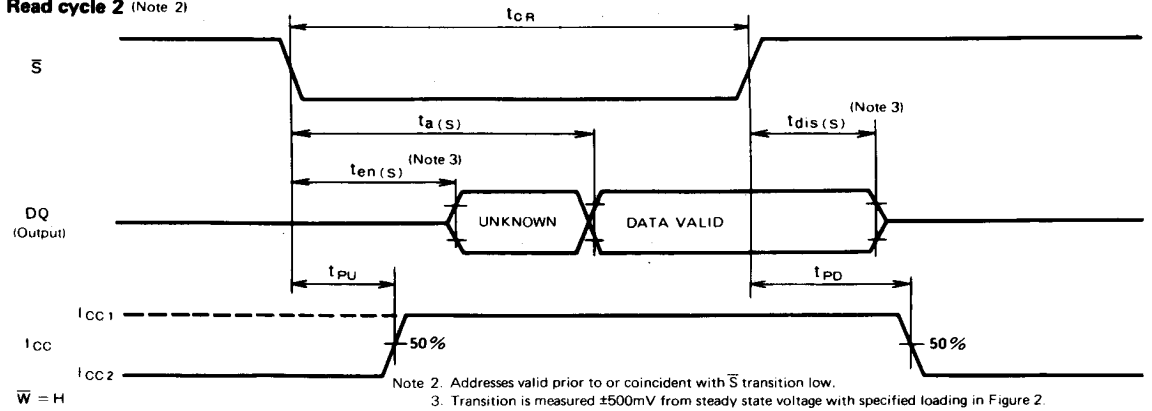
TIMING DIAGRAMS

Read cycle 1



$\bar{W} = H$
 $\bar{S} = L$

Read cycle 2 (Note 2)



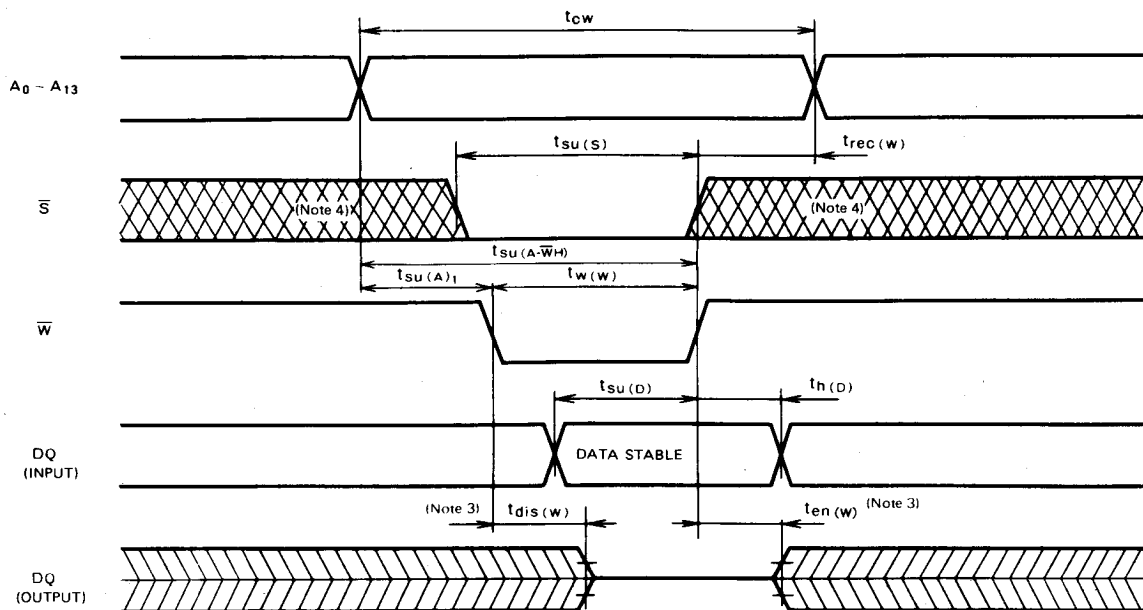
Note 2. Addresses valid prior to or coincident with \bar{S} transition low.
3. Transition is measured $\pm 500mV$ from steady state voltage with specified loading in Figure 2.



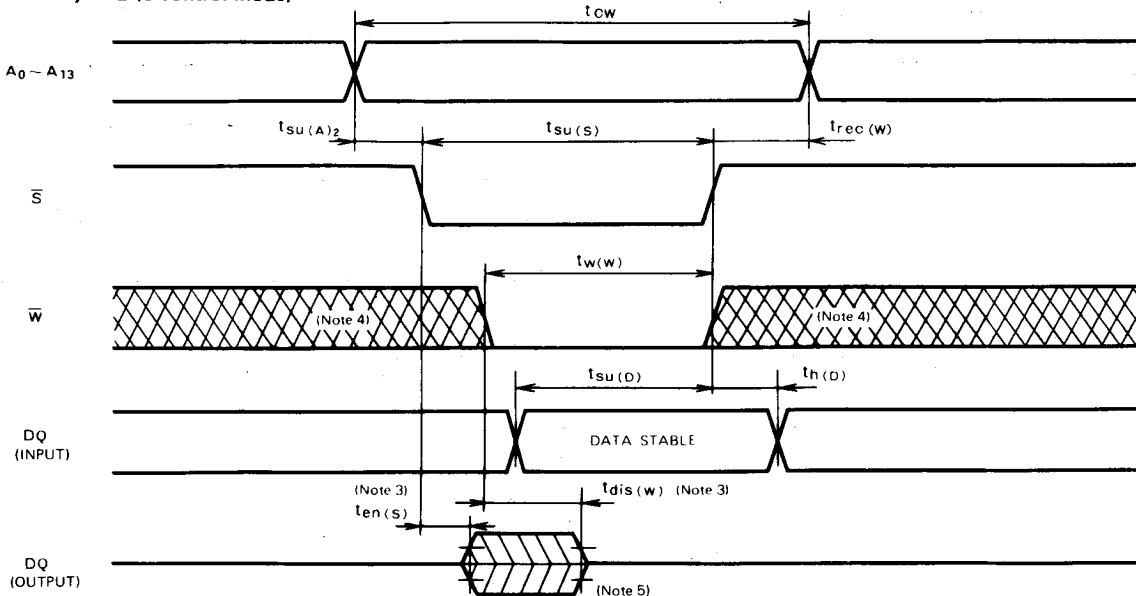
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TIMING DIAGRAMS

Write cycle 1 (\bar{W} control mode)



Write cycle 2 (\bar{S} control mode)



Note 4. Hatching indicates the state is don't care.

5. When the falling edge of \bar{W} is simultaneous or prior to the falling edge of \bar{S} , the output is maintained in the high impedance.